IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

Gary Chen et al.

App. No.

Unknown

Filed

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Examiner

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Group Art Unit

Unknown

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing thirty-two (32) references. All of these references are of record in U.S. Patent Application Number 10/234,577, filed August 30, 2002 ("the prior application"). Since these references are of record in the prior application, copies are not being submitted herewith. This Information Disclosure Statement is being filed within three months of the filing date of this application or upon filing if this is a CPA or RCE, and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1), (b)(2), or (b)(4).

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated:

7/3/03

By:

John R. King

Registration No. 34,362

Attorney of Record

Customer No. 20,995

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.109DC1D1		APPLICATION NO. Unknown	
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	DISCLOSURE STATEMENT			<u> </u>	·····
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				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1	3,968,565	07/13/76	Bertens et al.			
	2	4,528,066	07/09/85	Merkling, Jr., et al.			
	3	4,554,050	11/19/85	Minford, et al.			
	4	4,671,852	06/9/87	Pyke			
	5	4,787,958	11/29/88	Lytle			
·	6	4,900,690	02/13/90	Tamura			
	7	5,023,201	06/11/91	Stanasolovich et al.			
	8	5,100,826	03/31/92	Dennison			
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	11	5,425,392	06/20/95	Thakur, et al.			
	12	5,462,638	10/31/95	Datta, et al.			
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	26	6,136,211	10/24/00	Qian et al.			

EXAMINER	DATE CONSIDERED
	<u> </u>

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON.109DC1D1	APPLICATION NO. Unknown	
	DISCLOSURE STATEMENT / APPLICANT	APPLICANT Gary Chen et al.		
(USE SEVERAL	. SHEETS IF NECESSARY)	FILING DATE Herewith	GROUP Unknown	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	-	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
······································	27	6,221,746	04/24/01	Huang et al.				
	28	6,417,572	07/09/02	Chidambarrao et al.				

	-			FOREIGN PATENT DOCUMENTS				
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INITIAL						10	YES	NO
	29	0 560 324 A1	09/15/93	Europe				

EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
		Silicon Processing for the VLSI Era - Volume 1: Process Technology, Stanley Wolf and Richard N. Tauber, Lattice Press, Sunset Beach, California
*	31	US Publication No. US 2001/0003062 A1, Inventor: Rebecca Y. Tang, Pub. Date: June 7, 2001, Title: GATE SIDEWALL PASSIVATION TO PREVENT ABNORMAL TUNGSTEN POLYCIDE GROWTH
		US Publication No. US 2001/0019894 A1, Inventors: Peng et al., Pub Date: September 6, 2001, Title: PRE-HEAT STEP (OR CHAMBER) IMPLEMENTED IN PR DRY ASH MACHINES TO EFFECTIVELY ELIMINATE PR EXTRUSION (BUBBLE) AFTER ALLOY

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